

### Si4822DY

# Single N-Channel, Logic Level, PowerTrench MOSFET

### GeneralDescription

This N-Channel Logic Level MOSFET is produced using Fairchild Semiconductor's advanced PowerTrench process that has been especially tailored to minimize the on-state resistance and yet maintain superior switching performance.

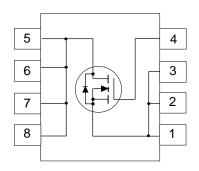
These devices are well suited for low voltage and battery powered applications where low in-line power loss and fast switching are required.

### **Features**

- Fast switching speed.
- Low gate charge.
- High performance trench technology for extremely low R<sub>DS(ON)</sub>.
- High power and current handling capability.







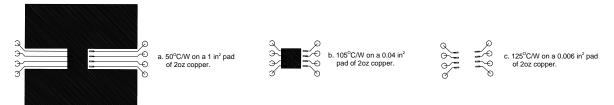
## **Absolute Maximum Ratings** $T_A = 25^{\circ}\text{C}$ unless other wise noted

Symbol	Parameter	Si4822DY	Units
/ <sub>DSS</sub>	Drain-Source Voltage	30	V
V <sub>GSS</sub>	Gate-Source Voltage	±20	V
D	Drain Current - Continuous (Note 1a)	12.5	A
	- Pulsed	50	
$P_{D}$	Power Dissipation for Single Operation (Note 1a)	2.5	W
	(Note 1b)	1.2	
	(Note 1c)	1	
$T_J$ , $T_{STG}$	Operating and Storage Temperature Range	-55 to 150	°C
THERMA	L CHARACTERISTICS		
R <sub>OJA</sub>	Thermal Resistance, Junction-to-Ambient (Note 1a)	50	°C/W
₹ <sub>øJC</sub>	Thermal Resistance, Junction-to-Case (Note 1)	25	°C/W

Symbol	Parameter	Conditions		Min	Тур	Max	Units
OFF CHAR	ACTERISTICS	•				ı	
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = 250 \mu\text{A}$		30			V
$\Delta BV_{DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient	I <sub>D</sub> = 250 μA, Referenced to 25 °C			33		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{DS} = 24 \text{ V}, \ V_{GS} = 0 \text{ V}$				1	μA
			$T_J = 55^{\circ}C$			10	μA
I <sub>GSSF</sub>	Gate - Body Leakage, Forward	$V_{GS} = 20 \text{ V}, V_{DS} = 0 \text{ V}$	•			100	nA
GSSR	Gate - Body Leakage, Reverse	$V_{GS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$				-100	nA
ON CHARAC	CTERISTICS (Note 2)						
$\Delta V_{GS(th)}/\Delta T_{J}$	Gate Threshold Voltage Temp. Coefficient	I <sub>D</sub> = 250 μA, Referenced	to 25 °C		-4.5		mV /°C
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$		1	1.6	3	V
			T <sub>J</sub> =125°C	0.8	1.3	2.4	1
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	$V_{GS} = 10 \text{ V}, I_D = 12.5 \text{ A}$	•		0.008	0.0095	Ω
			T <sub>J</sub> =125°C		0.012	0.016	
		$V_{GS} = 4.5 \text{ V}, I_D = 10.5 \text{ A}$	•		0.0105	0.013	
I <sub>D(ON)</sub>	On-State Drain Current	$V_{GS} = 10 \text{ V}, \ V_{DS} = 5 \text{ V}$		25			Α
g <sub>FS</sub>	Forward Transconductance	$V_{DS} = 15 \text{ V}, I_{D} = 12.5 \text{ A}$			35		S
DYNAMIC C	HARACTERISTICS						
C <sub>iss</sub>	Input Capacitance	$V_{DS} = 15 \text{ V}, \ V_{GS} = 0 \text{ V},$ $f = 1.0 \text{ MHz}$			2180		pF
Coss	Output Capacitance				500		pF
C <sub>rss</sub>	Reverse Transfer Capacitance				255		pF
SWITCHING	CHARACTERISTICS (Note 2)					1	
t <sub>D(on)</sub>	Turn - On Delay Time	$V_{DS} = 10 \text{ V}, I_{D} = 1 \text{ A}$			13	24	ns
t,	Turn - On Rise Time	$V_{GS} = 10 \text{ V}$ , $R_{GEN} = 6 \Omega$			14	26	ns
t <sub>D(off)</sub>	Turn - Off Delay Time				43	70	ns
t,	Turn - Off Fall Time				15	27	ns
$Q_g$	Total Gate Charge	$V_{DS} = 15 \text{ V}, I_{D} = 12.5 \text{ A},$			23	33	nC
$Q_{gs}$	Gate-Source Charge	V <sub>GS</sub> = 5 V			7		nC
$Q_{gd}$	Gate-Drain Charge				11		nC
	RCE DIODE CHARACTERISTICS AND MAXIM	IUM RATINGS			Т	1	1
l <sub>s</sub>	Maximum Continuous Drain-Source Diode Fo					2.1	Α
$V_{SD}$	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = 2.1 \text{ A} \text{ (Note 2)}$			0.72	1.2	V

#### Notes

<sup>1.</sup>  $R_{g,h}$  is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins.  $R_{g,C}$  is guaranteed by design while  $R_{g,C,h}$  is determined by the user's board design.



Scale 1 : 1 on letter size paper

2. Pulse Test: Pulse Width  $\leq$  300µs, Duty Cycle  $\leq$  2.0%.

## **Typical Electrical Characteristics**

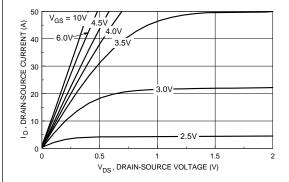


Figure 1. On-Region Characteristics.

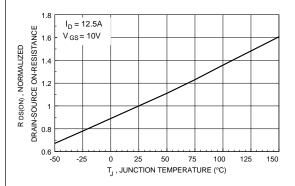


Figure 3. On-Resistance Variation with Temperature.

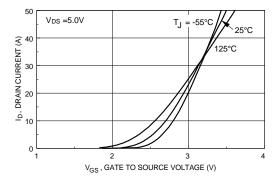


Figure 5. Transfer Characteristics.

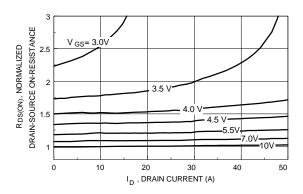


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

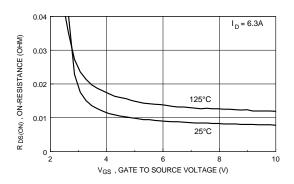


Figure 4 . On Resistance Variation with Gate-to-Source Voltage.

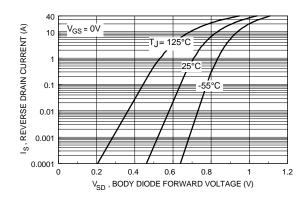


Figure 6 . Body Diode Forward Voltage Variation with Source Current and Temperature.

## **Typical Electrical And Thermal Characteristics**

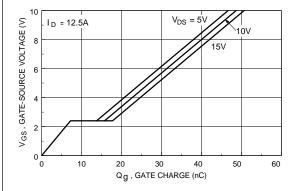


Figure 7. Gate Charge Characteristics.

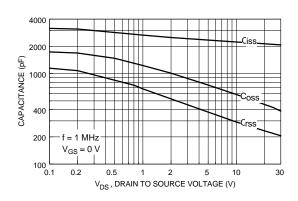


Figure 8. Capacitance Characteristics.

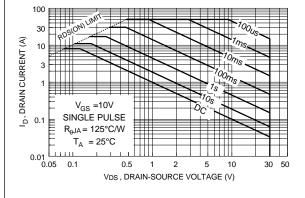


Figure 9. Maximum Safe Operating Area.

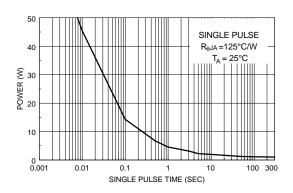


Figure 10. Single Pulse Maximum Power Dissipation.

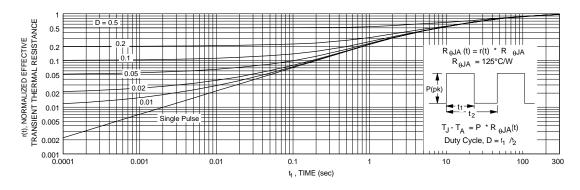


Figure 11. Transient Thermal Response Curve .

Thermal characterization performed using the conditions described in Note 1c.

Transient thermal response will change depending on the circuit board design.

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